

PTO/SB/08 (2-92)

Sheet 1 of 1

Form PTO-1449

INFORMATION DISCLOSURE CITATION
IN AN APPLICATION

(Use several sheets if necessary)

Docket Number 333772000800

Application Number 10/772,434

Applicant

Ramachandran KRISHNASWAMY et al.

Filing Date February 6, 2004

Group Art Unit 2829

Mailing Date September 3, 2004

U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate
SL	1.	02/27/2001	6,195,774	Jacobson			
SL	2.	01/31/1996	5,488,573	Brown et al.			
SL	3.	06/13/2002	2002/0073375 A1	Hollander			

FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO

OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
SL	4.	International Search Report mailed on June 23, 2004, for PCT application no PCT/JP2004/001649 filed on February 16, 2004, 4 pages.
SL	5.	Written Opinion mailed on June 23, 2004, for PCT application no PCT/JP2004/001649 filed on February 16, 2004, 8 pages.

EXAMINER: /Suzanne Lo/ (07/06/2006)

DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

sf- 1739467PTO/SB/ 08 (2-92)

Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

Form PTO-1449

Docket Number 333772000800

Application Number 10/772,434

**INFORMATION DISCLOSURE CITATION
IN AN APPLICATION**

(Use several sheets if necessary)

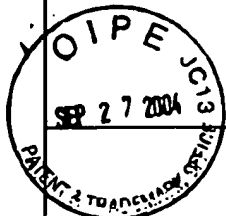
Applicant

Ramachandran KRISHNASWAMY et al.

Filing Date February 6, 2004

Group Art Unit 2829

Mailing Date September 21, 2004


U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate
SL	1.	07/29/2003	6,601,018	Logan			
SL	2.	07/30/2002	6,427,223	Kim et al.			
SL	3.	06/11/2002	6,405,364	Bowman-Amuah			
SL	4.	04/06/1999	5,892,949	Noble			

FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO

OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

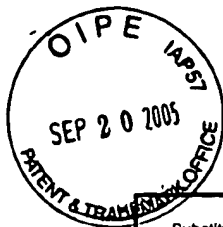
Examiner Initials	Ref. No.	Title

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ALTERNATIVE TO PTO/SB/08 a/b (07-05)

Substitute for form 1449/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Application Number	10/772,434
				Filing Date	February 6, 2004
				First Named Inventor	Ramachandran KRISHNASWAMY
				Art Unit	2829
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	333772000800

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
SL	1.	US-2003/0005375-A1	01-02-2003	Krech, Jr. et al.	
SL	2.	US-2005/0154551-A1	07-14-2005	Pramanick et al.	
SL	3.	US-2005/0022087-A1	01-27-2005	Pramanick et al.	
SL	4.	US-6,028,439-A	02-22-2000	Arkin et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	MM-DD-YYYY			
SL	5.	WO-2004/072669-A1	08-26-2004	Advantest Corporation		
SL	6.	WO-2004/072670-A1	08-26-2004	Advantest Corporation		

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NON PATENT LITERATURE DOCUMENTS				
Examiner Initials ¹	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		T ²
SL	7.	Chang, E. et al. (1998). "A Scalable Architecture for VLSI Test," <i>IEEE, Proceedings International Test Conference 1998</i> , Washington, DC. Paper 20.2, pp. 500-506.		
SL	8.	Conti, D. R. (2002). "Mission Impossible? Open Architecture ATE," <i>IEEE, Proceedings International Test Conference 2002</i> , Washington, DC. Panel P5.1, p. 1207.		
SL	9.	Evans, A.C. (1999). "Applications of Semiconductor Test Economics, and Multisite Testing to Lower Cost of Test," <i>IEEE, Proceedings International Test Conference 1999</i> , Washington, DC. Paper 5.2, pp. 113-123.		
SL	10.	Fan, D. et al. (2003). "Case Study - Using STIL as Test Pattern Language," <i>NPTesT, Inc. LLC, ITC International Test Conference</i> , Paper 32.3, pp. 811-817.		
SL	11.	Mirizzi, D.J. et al. (1993). "Implementation of Parallel Site Test on an 8-Bit Configurable Microcontroller," <i>IEEE, Proceedings International Test Conference 1993</i> , Washington, DC. Paper 8.3, pp. 226-235.		
SL	12.	Perez, S.M. (2002). "The Consequences of an Open ATE Architecture," <i>IEEE, Proceedings International Test Conference 2002</i> , Washington, DC. Panel P5.4, p. 1210.		
SL	13.	Perez, S.M. et al. (July 16, 2003). "Open Architecture Test System: The New Frontier," <i>28th IEEE/CPMI/SEMI International Electronics Manufacturing Technology Symposium</i> , San Jose, CA, July 16-18, 2003, pp. 211-214.		
SL	14.	Schoettmer, U. et al. (1995). "Challenging the 'High Performance - High Cost' Paradigm in Test," <i>IEEE, Proceedings International Test Conference 1995</i> , Washington, DC. Paper 37.1, pp. 870-879.		
SL	15.	Simpson, W.R. (1995). "Cutting the Cost of Test; the Value-added Way," <i>IEEE, Proceedings International Test Conference 1995</i> , Washington, DC. Paper 41.2, p. 921.		
SL	16.	West, B.G. (2002). "Open ATE Architecture: Key Challenges," <i>IEEE, Proceedings International Test Conference 2002</i> , Washington, DC. Panel P5.6, p. 1212.		

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¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature	/Suzanne Lo/ (07/06/2006)	Date Considered	
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ALTERNATIVE TO PTO/SB/08a/b (07-05)

Substitute for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)			Complete if Known		
			Application Number	10/772,434	
			Filing Date	February 6, 2004	
			First Named Inventor	Ramachandran KRISHNASWAMY	
			Art Unit	2128	
			Examiner Name	Not Yet Assigned	
Sheet	1	of	1	Attorney Docket Number	333772000800

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
SL	1.	US-2003/0217343-A1	11-20-2003	Rajsuman et al.	
SL	2.	US-4,807,161-A	02-21-1989	Comfort et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
SL	3.	DE-10031536-A1	01-18-2001	Advantest Corp.	Translation of Abstract Only	

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Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		T ²
SL	4.	International Search Report mailed on February 16, 2006 for PCT Application No. PCT/JP2005/009813 filed on May 23, 2005, 5 pages.		
SL	5.	Portelli, B. et al. (May 22, 1989). "Demonstration of Avionics Module Exchangeability via Simulation (DAMES) Program Overview," <i>Proceedings of the IEEE 1989 Natl Aerospace and Elect. Conf. (NAECON 1989)</i> , Dayton, OH, vol. 2:660-667.		
SL	6.	Rajsuman, R. (Jan. 30, 2004). "An Overview of the Open Architecture Test System," <i>Proceedings of the 2nd IEEE Intl Workshop on Elect. Design, Test, and Applications (Delta'04)</i> , pp. 1-6.		
SL	7.	Semiconductor Test Consortium. "ATE Open Architecture Initiative," (October 8, 2002). located at < http://www.semitest.org/site/News/News_Files/file_news2 > last visited on March 8, 2006, 12 pages.		

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Examiner Signature	/Suzanne Lo/ (07/06/2006)	Date Considered	
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